

# Hardware Meeting

29.2.2024

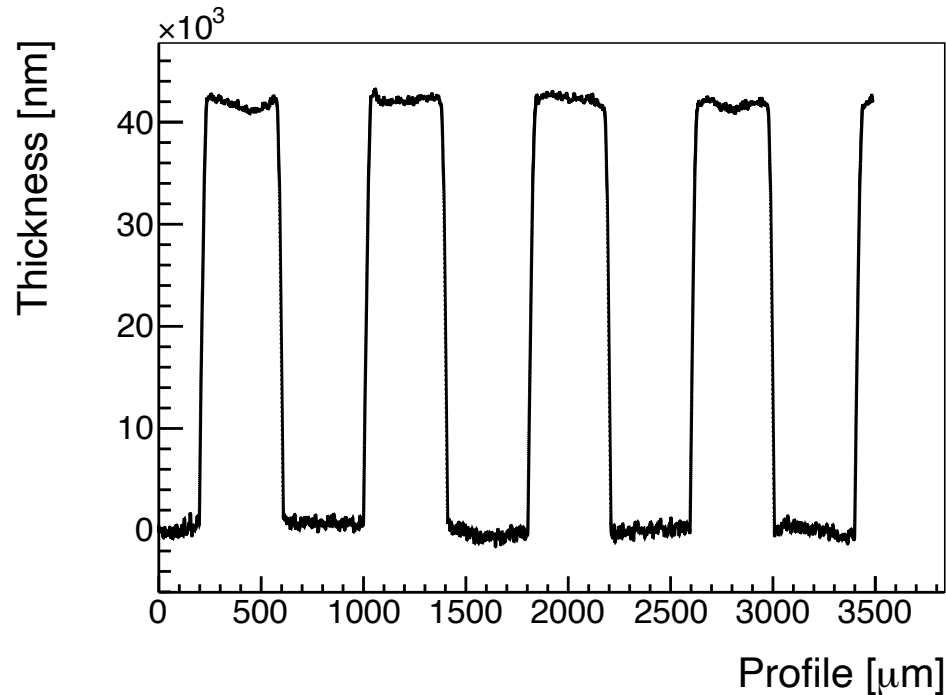
Katrin Penski

# Converter Layers

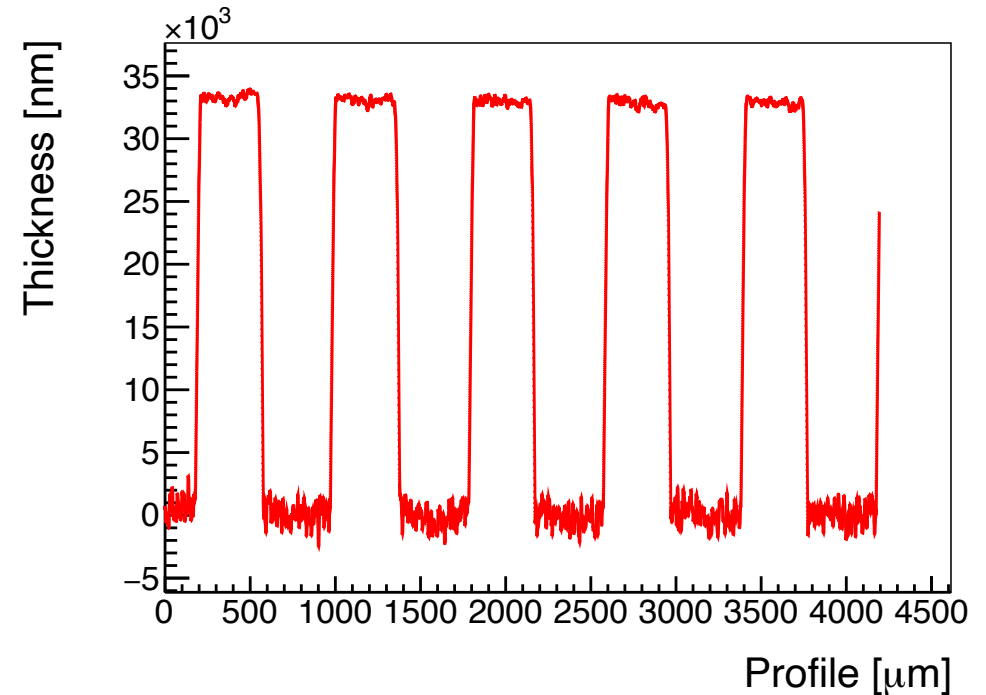
Converter Layers (bought)	Double-Sided Cu	Expected Thickness [mm]	Measured Thickness
1550 $\mu\text{m}$ FR4 + 35 $\mu\text{m}$ Cu	yes	1.620	1.59 $\pm$ 0.01
300 $\mu\text{m}$ FR4 + 35 $\mu\text{m}$ Cu	yes	0.370	0.32
100 $\mu\text{m}$ PI + 35 $\mu\text{m}$ Cu	yes	0.170	0.17
100 $\mu\text{m}$ PI + 18 $\mu\text{m}$ Cu	yes	0.136	0.14
50 $\mu\text{m}$ PI + 35 $\mu\text{m}$ Cu	yes	0.120	0.12
50 $\mu\text{m}$ PI + 18 $\mu\text{m}$ Cu	yes	0.086	0.09

- PI: Polyimide
- thickness measurement with digital caliper
- for layers made of Kapton show agreement
- FR4 layers show differences in thickness  $\rightarrow$  further investigation

# FR4 Layers – Copper Thickness



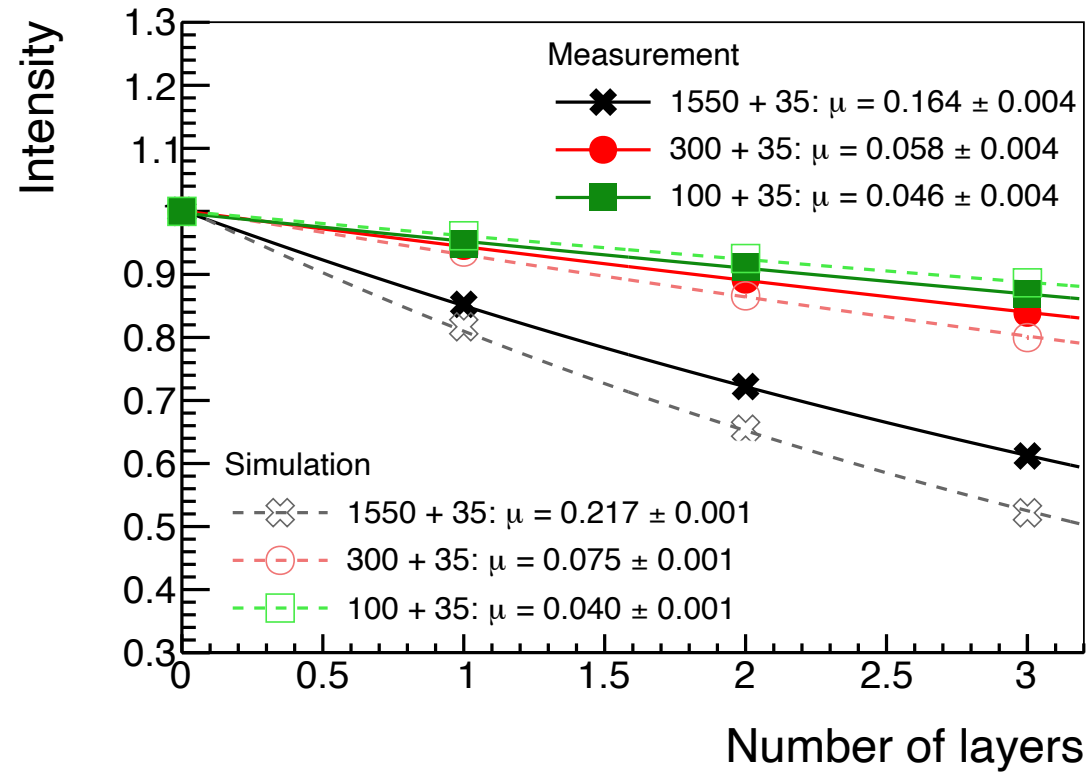
1550 FR4 + 35 Cu



300 FR4 + 35 Cu

- FR4 thicknesses (taking 35  $\mu\text{m}$  of Cu on both sides):
  - 1520  $\mu\text{m}$  FR4 instead of 1550  $\mu\text{m}$
  - 250  $\mu\text{m}$  FR4 instead of 300  $\mu\text{m}$  FR4
- for 1520  $\mu\text{m}$  layer it is 42  $\mu\text{m}$  strip thickness  $\rightarrow$  is it Cu or glue?  $\rightarrow$  currently use 35  $\mu\text{m}$  Cu

# Recap - Photon Absorption Measurement



- discrepancies between simulation and measurement for FR4

# FR4 Layers

- product: ISOLA Duraver DE104

(<https://www.multi-circuit-boards.eu/support/download/datenblaetter.html>)

Construction	Resin Content%	Thickness (inch)	Thickness (mm)	Dielectric Constant (DK)/ Dissipation Factor (DF)				
				100 MHz	500 MHz	1 GHz	2 GHz	5 GHz
2 x 1652	42%	0.010	0.25	4.67 0.0140	4.64 0.0150	4.62 0.0170	4.60 0.0180	4.55 0.0180
8 x 7628	42%	0.060	1.52	4.67 0.0140	4.64 0.0150	4.62 0.0170	4.60 0.0180	4.55 0.0180

(<https://www.isola-group.com/pcb-laminates-prepreg/de104-laminate-and-prepreg/>)

- 42 % brominated Epoxy Resin, 58 % Fibrous Glass → composition?

# FR4 Layers – Fibrous Glass Properties

	Property		E-Glass
	Advantage	Disadvantage	
<b>SiO<sub>2</sub></b>	Dk, Df	Drilability	52-56%
<b>CaO</b>		Dk	20-25%
<b>Al<sub>2</sub>O<sub>3</sub></b>		Df	12-16%
<b>B<sub>2</sub>O<sub>3</sub></b>	Dk, Dk		5-10%
<b>MgO</b>	Meltability	Dk	0-5%
<b>Na<sub>2</sub>O, K<sub>2</sub>O</b>		Dk, Df, Durability	0-1%
<b>TiO<sub>2</sub>, LiO<sub>2</sub></b>	Meltability		0%

Used now:  
 54 % SiO<sub>2</sub>  
 14 % Al<sub>2</sub>O<sub>3</sub>  
 22 % CaO  
 7 % B<sub>2</sub>O<sub>3</sub>  
 2 % MgO  
 1 % Na<sub>2</sub>O



- [https://www.isola-group.com/wp-content/uploads/Isola-Glass-Fabric-04\\_2022.pdf](https://www.isola-group.com/wp-content/uploads/Isola-Glass-Fabric-04_2022.pdf)

# FR4 Layers – Brominated Epoxy Resin

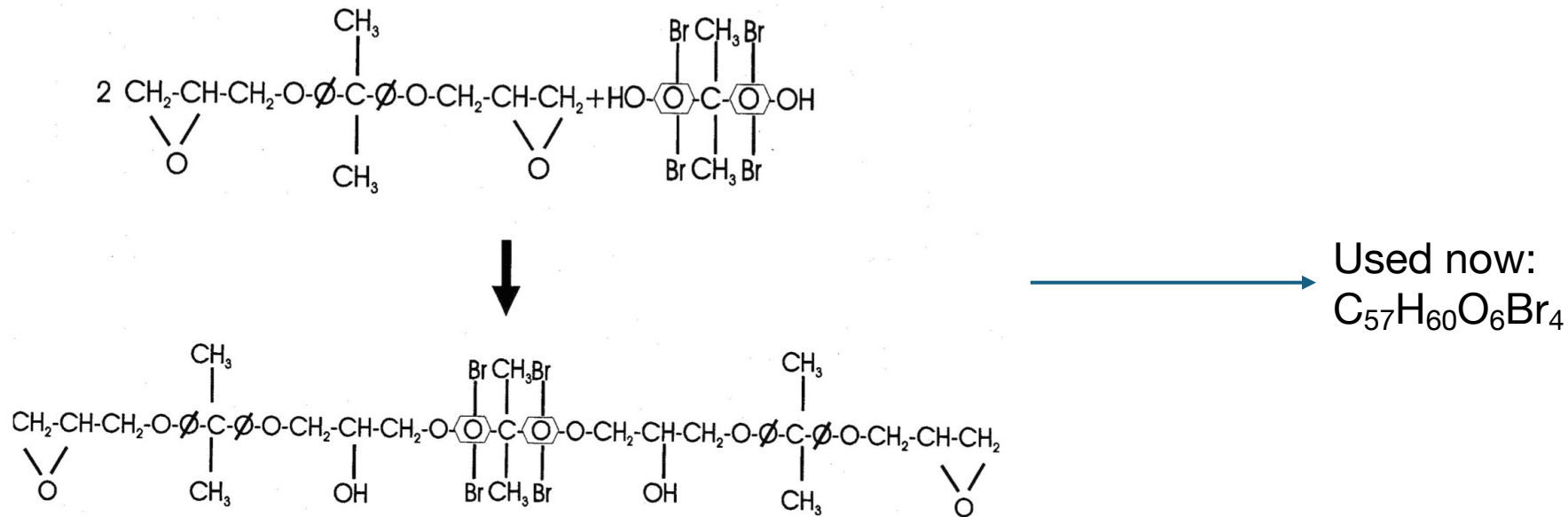
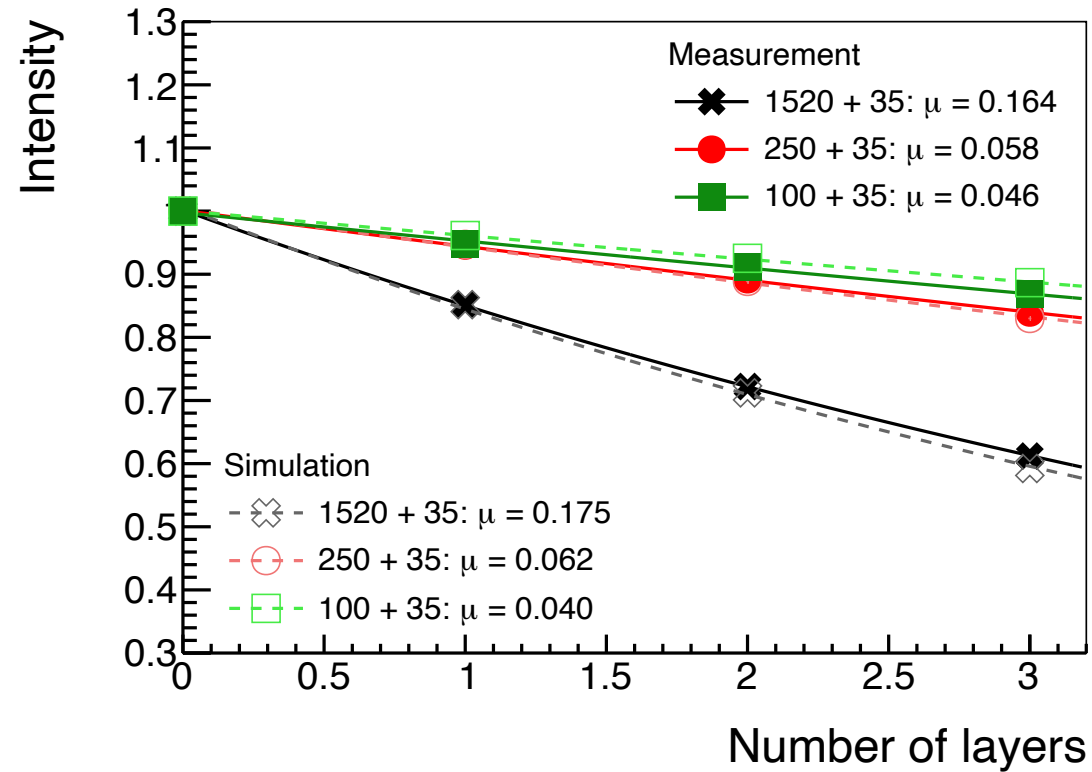


Figure 1 – Brominated Epoxy Resin

- <http://isola-group.com/wp-content/uploads/High-Tg-Bromine-free-Laminates-for-PWB-Applications.pdf>
- new FR4 composition: 10.7 wt% Br (in this paper 7.4 wt%. Reported for similar material from ISOLA → DEBROMINATION OF DUROPLASTIC FLAME-RETARDED POLYMERS by Katrin Mackenzie and Frank-Dieter Kopinke )

# Photon Absorption Measurement – New Material

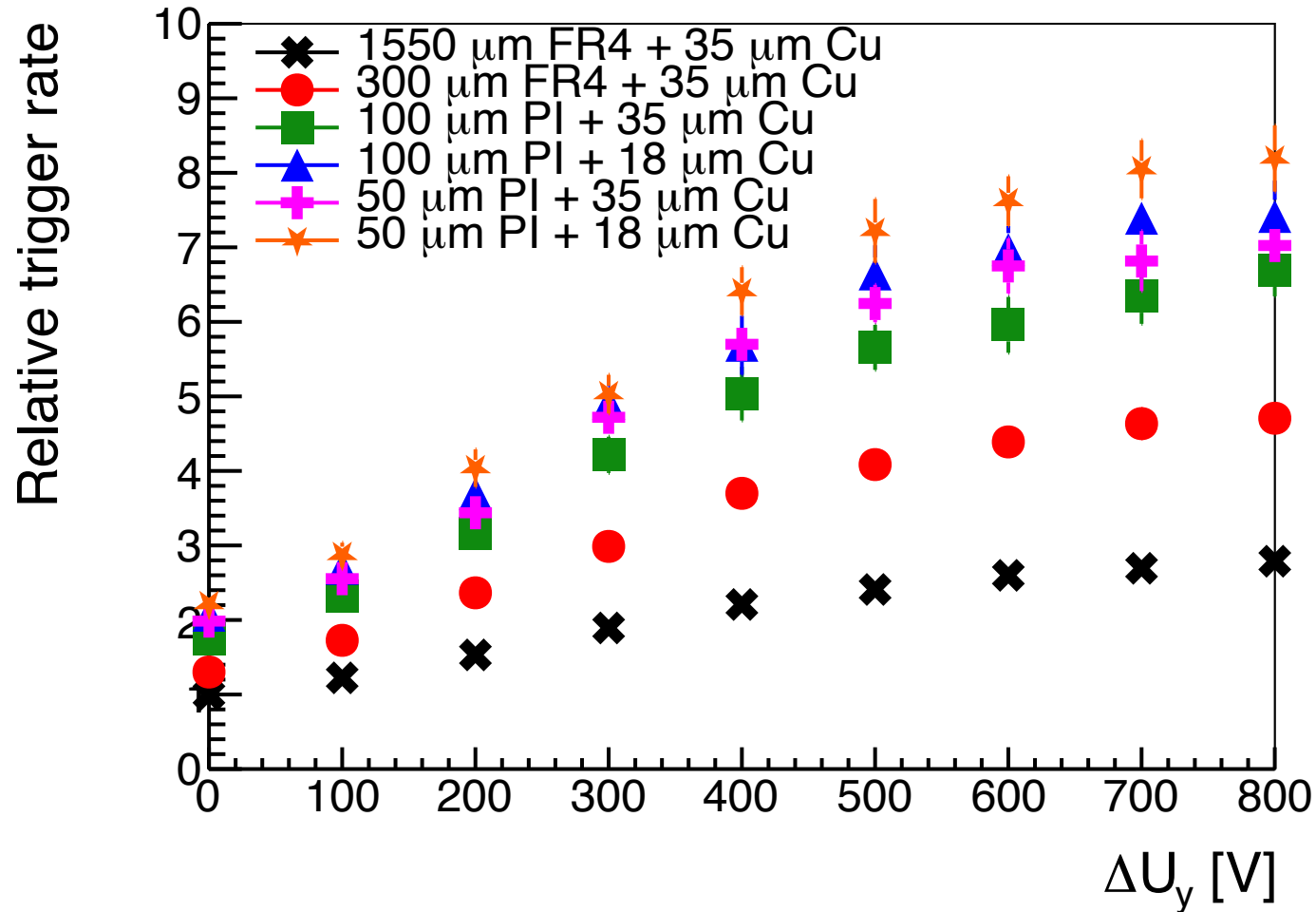


- Better agreement between simulation and measurement :)



# Converter Layer Measurement

# Measurement – Converter Layers

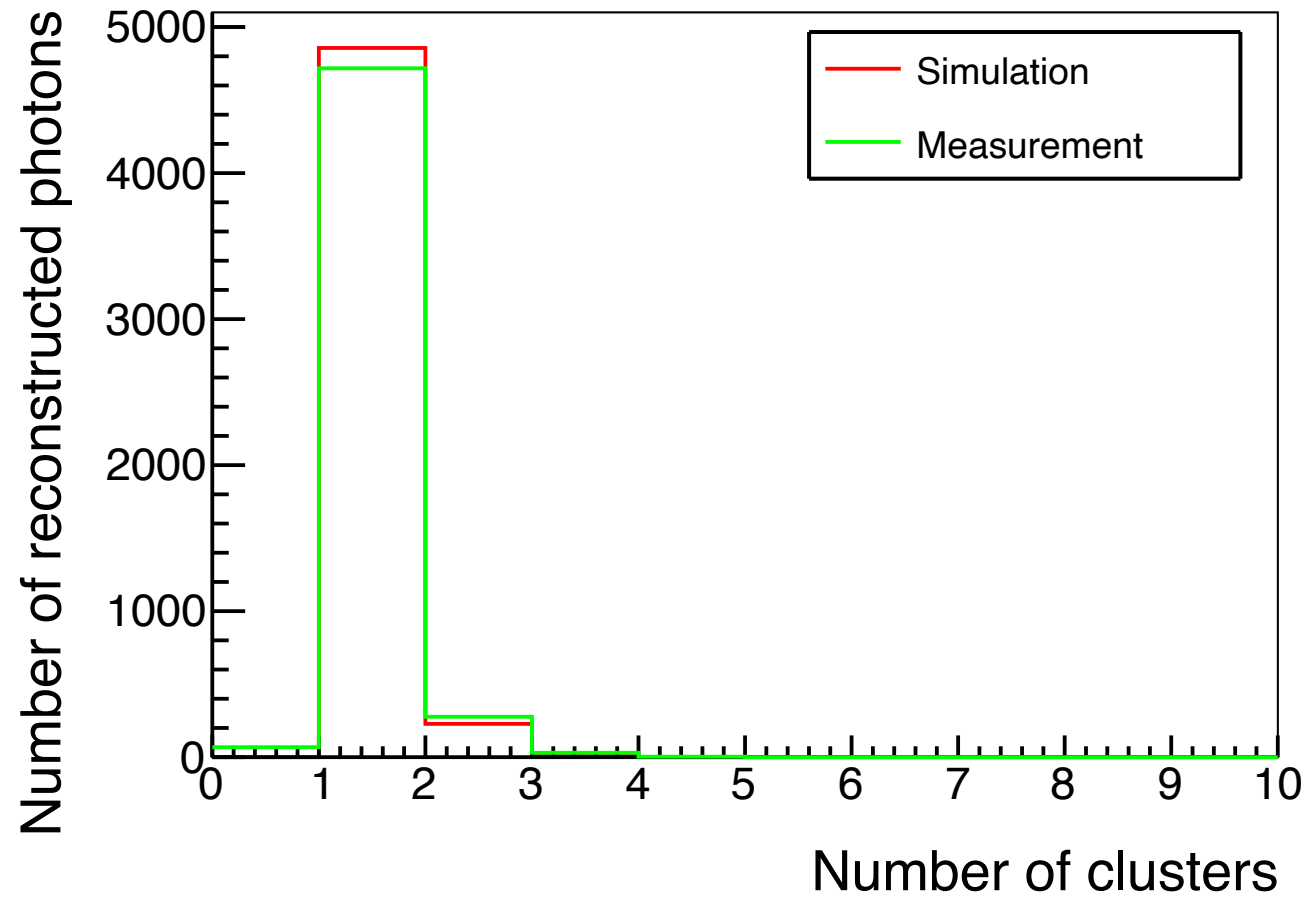


- still old labelling
- used climate cabinet and pressure system  
→ GEM voltage correction (maybe still adaption necessary)
- 50  $\mu\text{m}$  PI + 18  $\mu\text{m}$  Cu best performing layer up to now 😊
- Simulation doesn't show any agreement for different materials 😞

# Comparison Measurement and Simulation

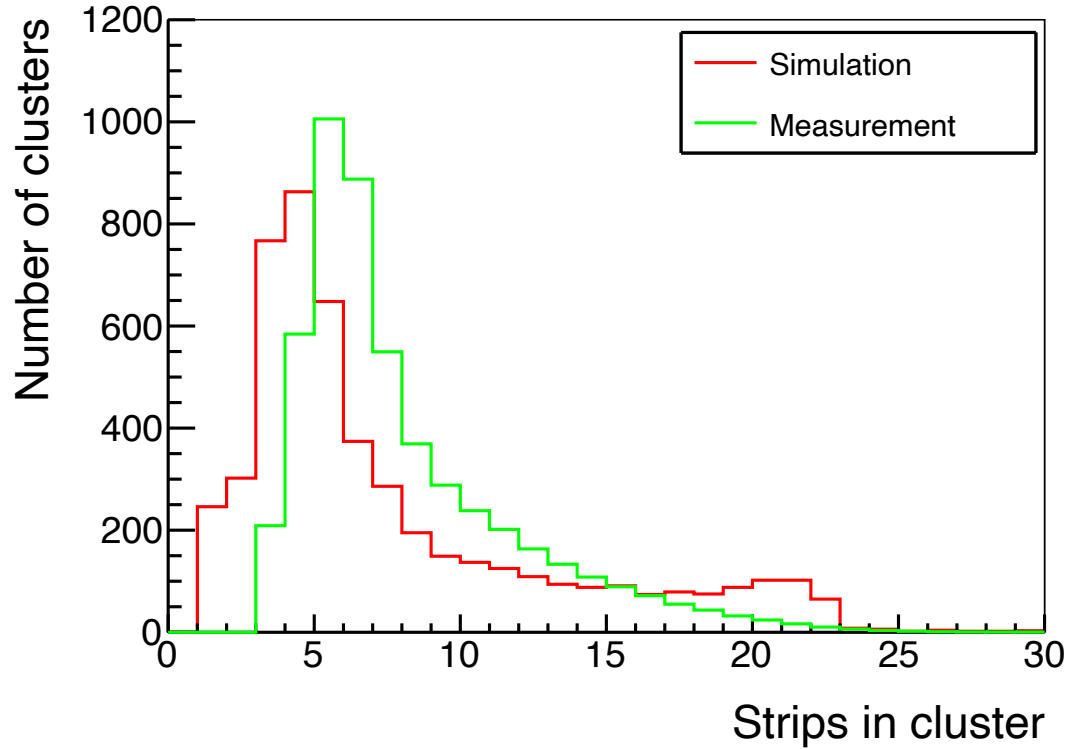
(Preliminary)

# Cluster No

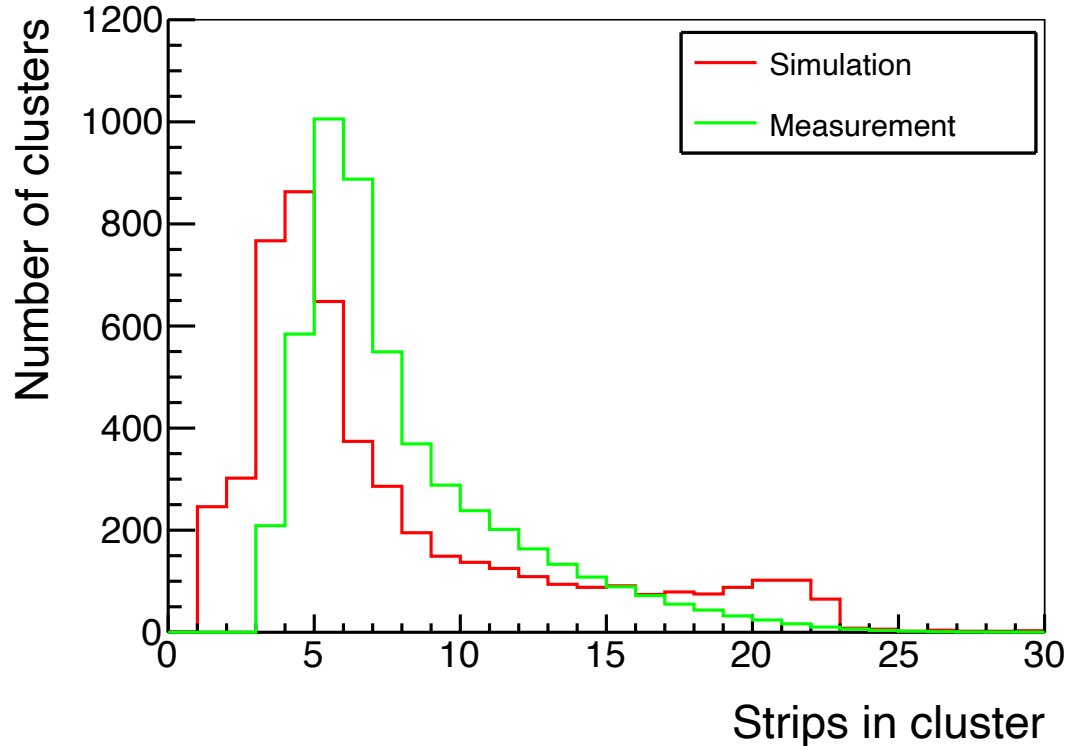


- For 1550  $\mu\text{m}$  and 35  $\mu\text{m}$  layers at  $dU_y=600\text{V}$  und  $dU_x=0\text{V}$
- Show agreement

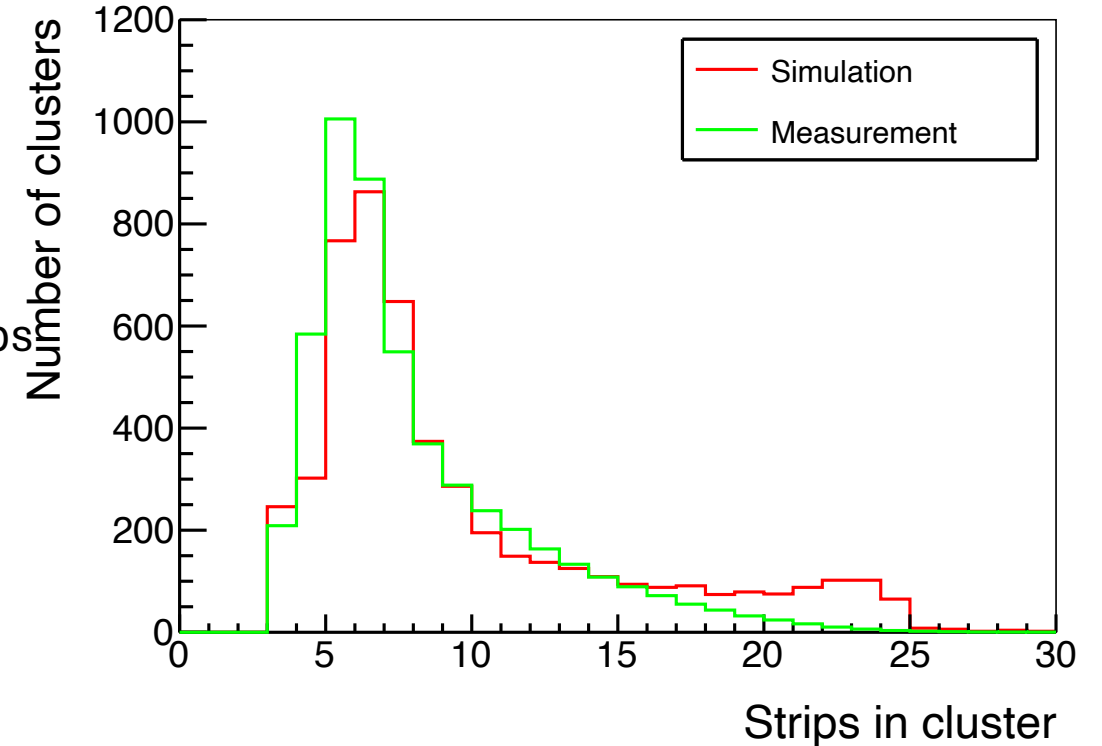
# Strips per Cluster (x-direction)



# Strips per Cluster (x-direction)

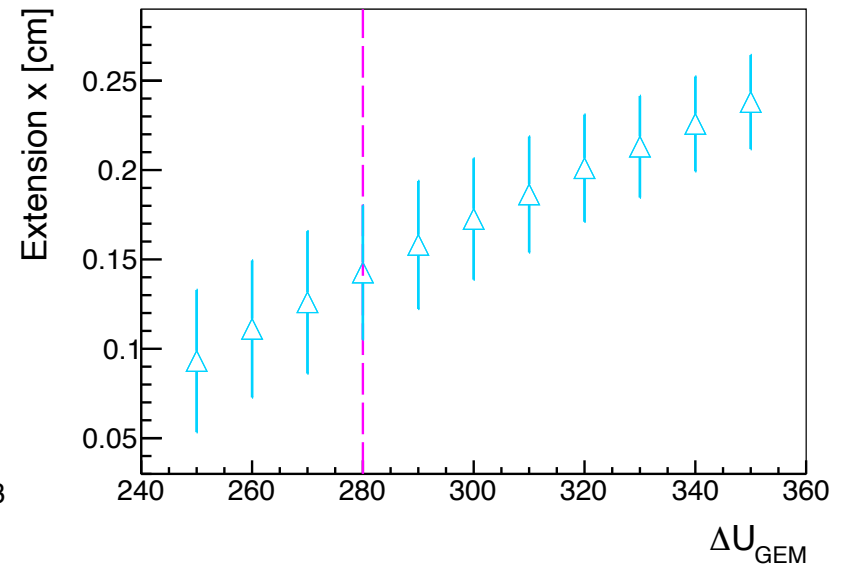
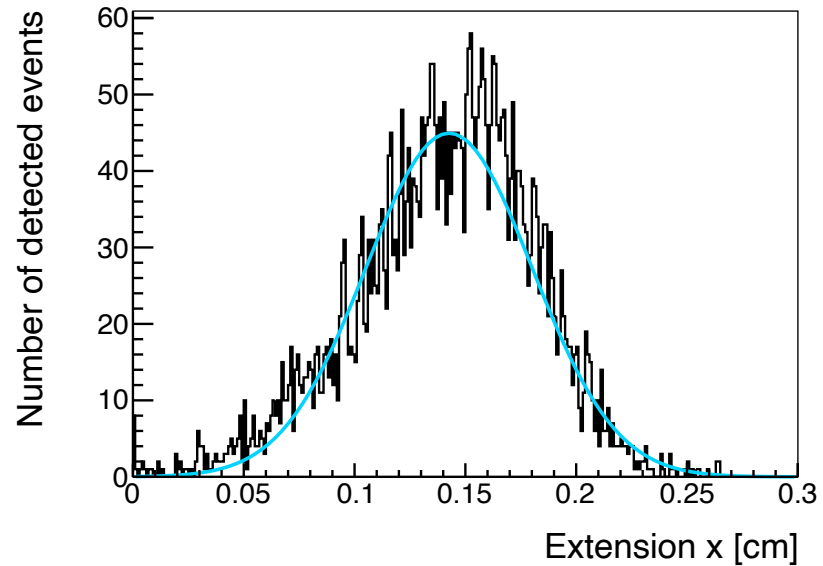
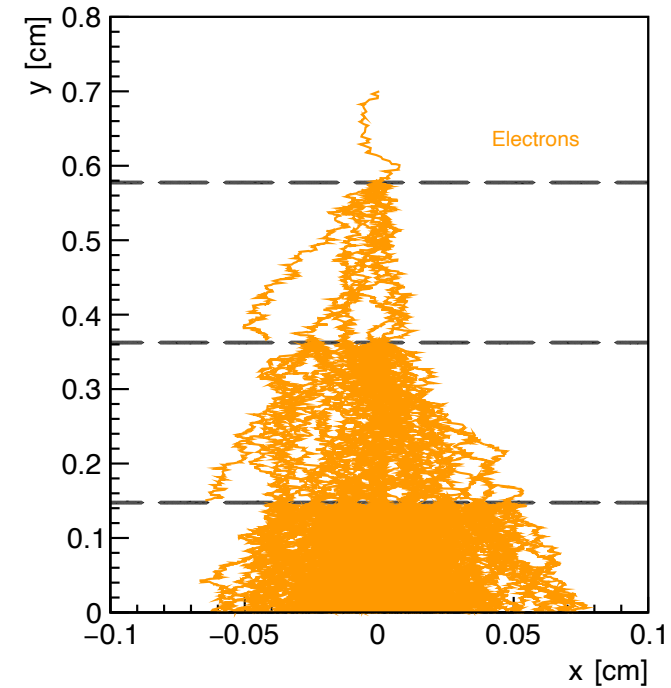


Shift by 2 strips  
→



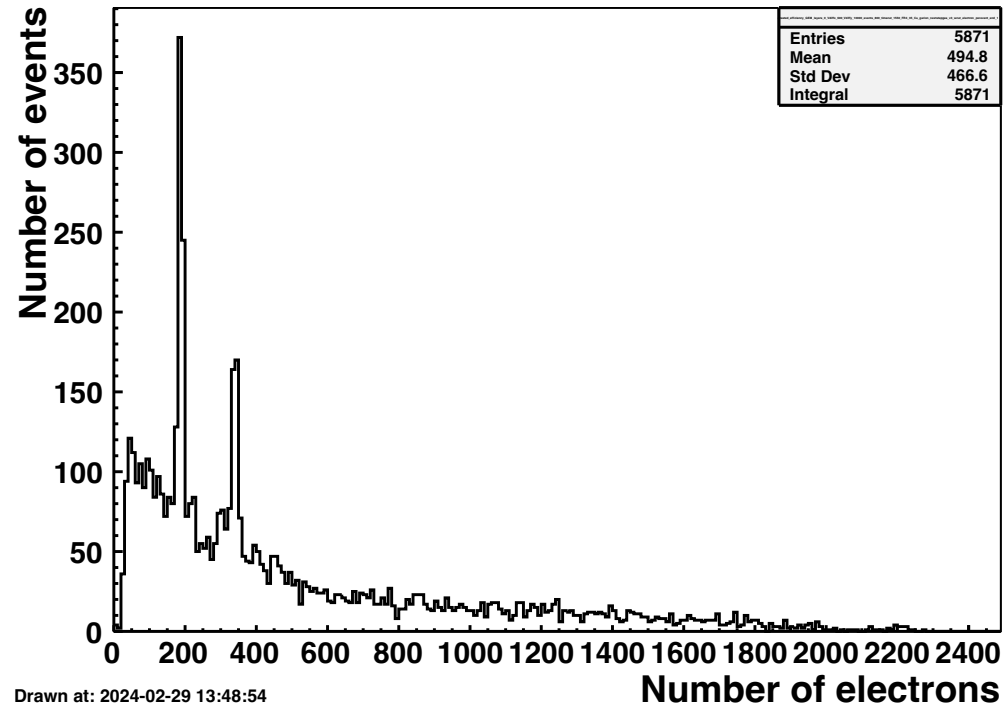
- with 2 strip offset correction same shape -> only tail differs
- Physical reason for this behaviour -> TO DO

# Is this Shift valid? -> Garfield Simulation



- Simulation suggests an offset of 3 strips for electron avalanche (currently under investigation)

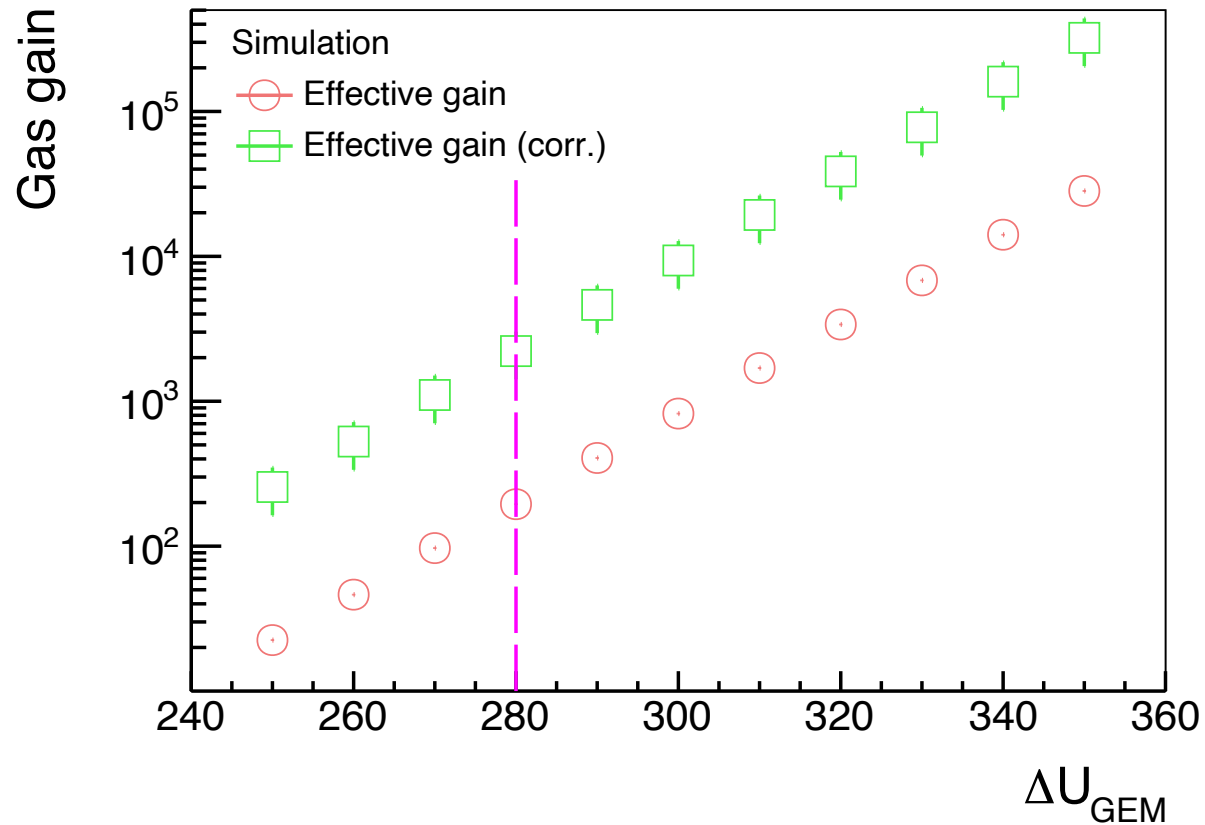
# Cluster Charge



- Simulation: Peak at around 180 electrons after drift @ first GEM
- Reason for this peaks still under investigation

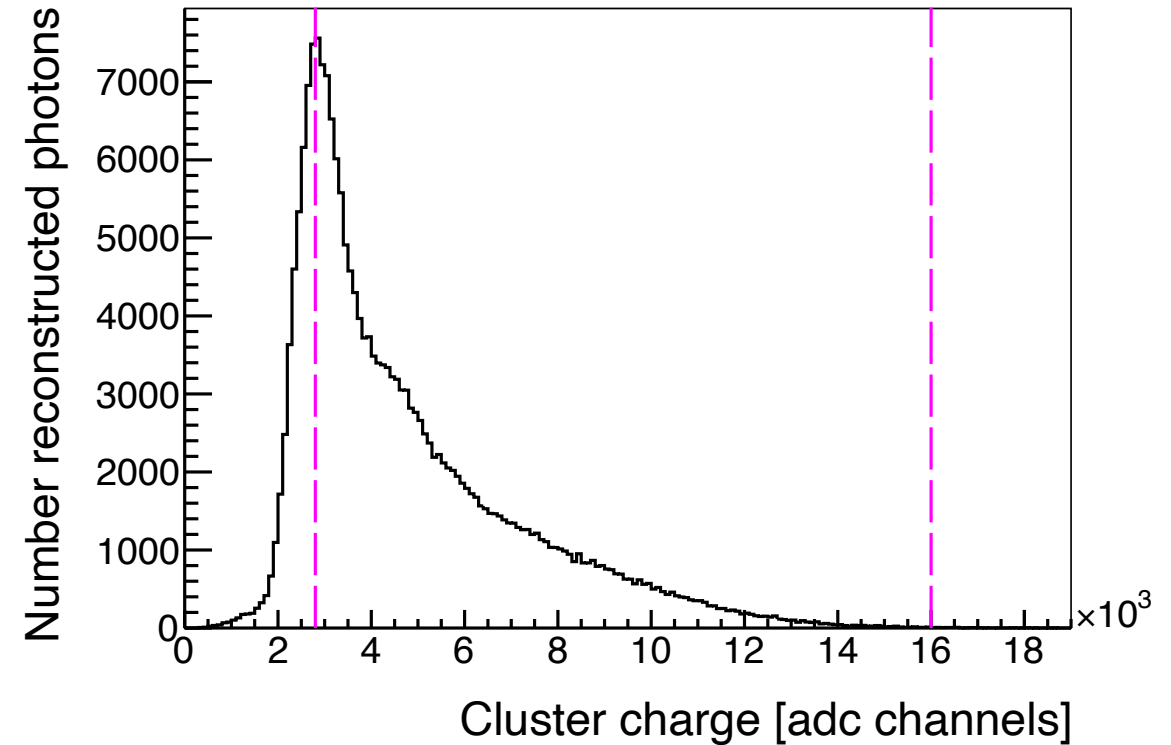
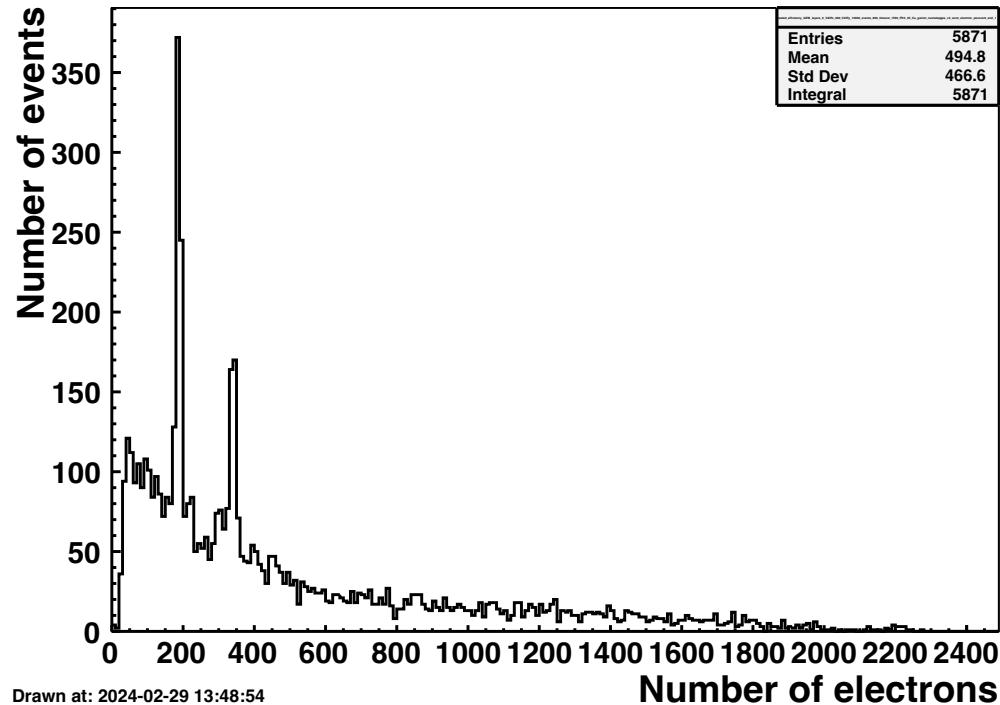


# Garfield Simulation: Amplification



- Amplification between 1505 -3104
- Plot here: 2209

# Cluster Charge



- Simulation: Peak at around 180 electrons after drift @ first GEM
  - 1ADC count is 230 e<sup>-</sup> -> **Expected peak between 1177 and 2429 ADC counts**
- > **Currently at about 2800 ADC counts for this measurement -> close to expected value -> check for pressure influence**